

Historical Data **Since 1959** IEEE International Ultrasonics Symposium (**IUS**) Conferences

and

Statistics and Time Curves of the 2008 IEEE IUS

Note: A Microsoft Excel version of these plots for details of the data is accessible at: https://ewh.ieee.org/conf/ius_2008/z_doc_misc/0_oper_ius2008_plots.xls

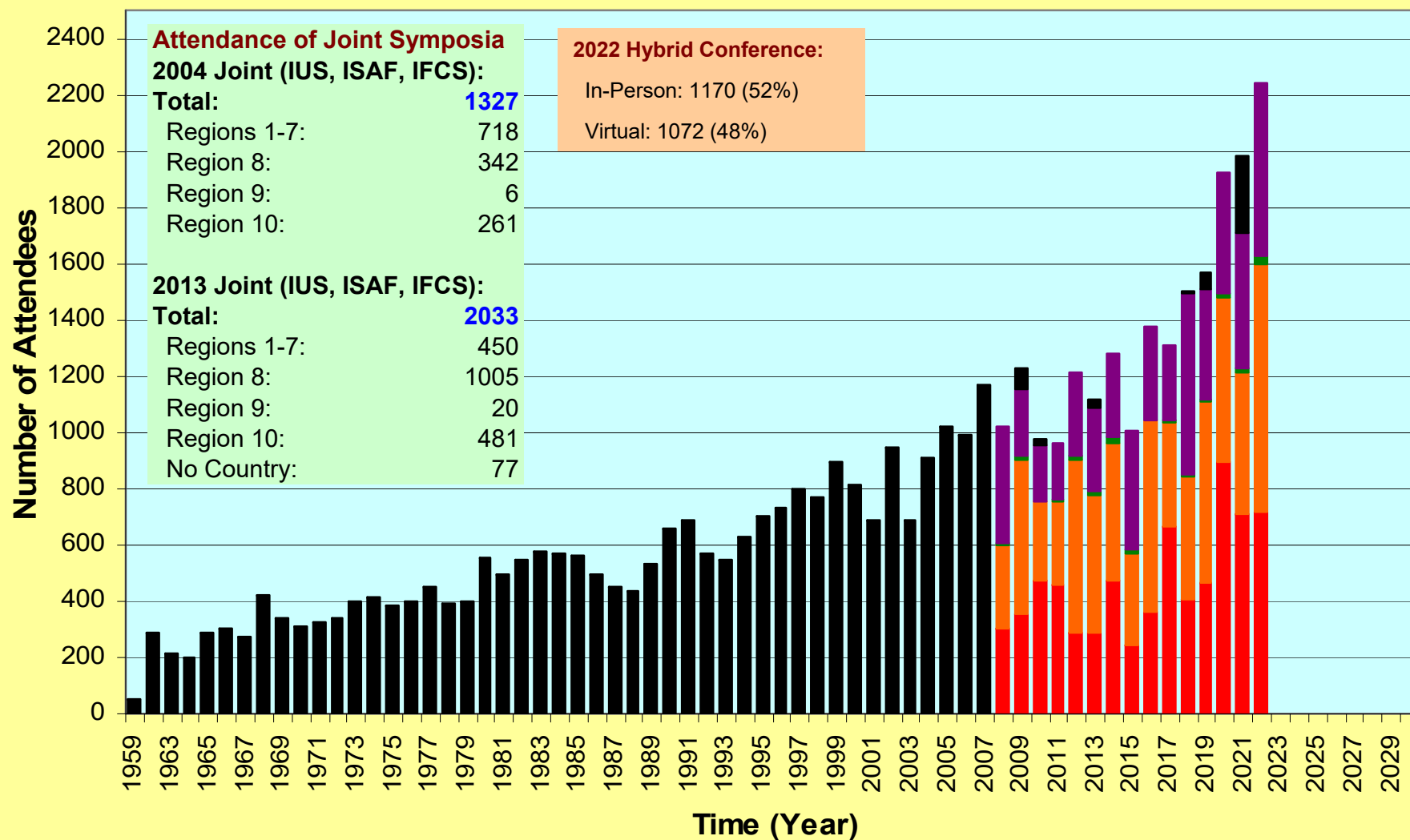
Notes

Collecting historical data for the charts in this document was made possible with the help from Dr. John Kosinski, the General Chair of the 2007 IEEE IUS, Dr. Fred S. Hickernell, a former Newsletter Editor of the IEEE Ultrasonics, Ferroelectrics, and Frequency Control Society (UFFC-S), Dr. Herman van der Vaart, the Finance Chair of the UFFC-S, and others. Many data were obtained from the Newsletters and the Administrative Committee (AdCom) Minutes of UFFC-S on the web, Program Books of the conferences, Conference Proceedings, and miscellaneous sources such as the Federation of Animal Science Societies (FASS) in the past and from the presentations of Dr. Maurício Pereira da Cunha, the TPC Chair of the 2007 IEEE IUS.

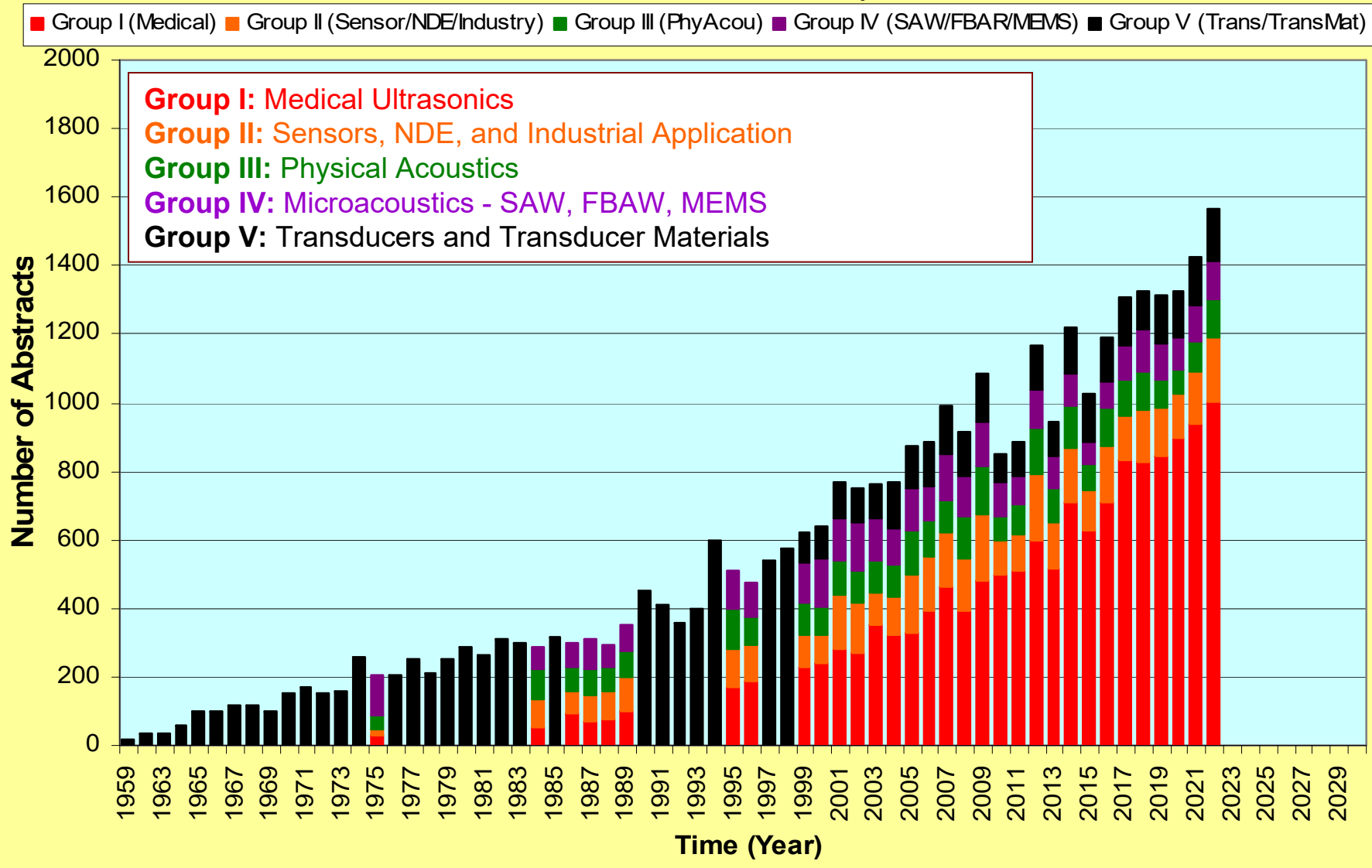
We appreciate all who have contributed the data and those who have made the AdCom Minutes, Newsletters, and Proceedings available on the web.

of Attendees of the IEEE International Ultrasonics Symposia (IUS) by IEEE Regions (Since 1959) - "0" values mean that data are not available for those years

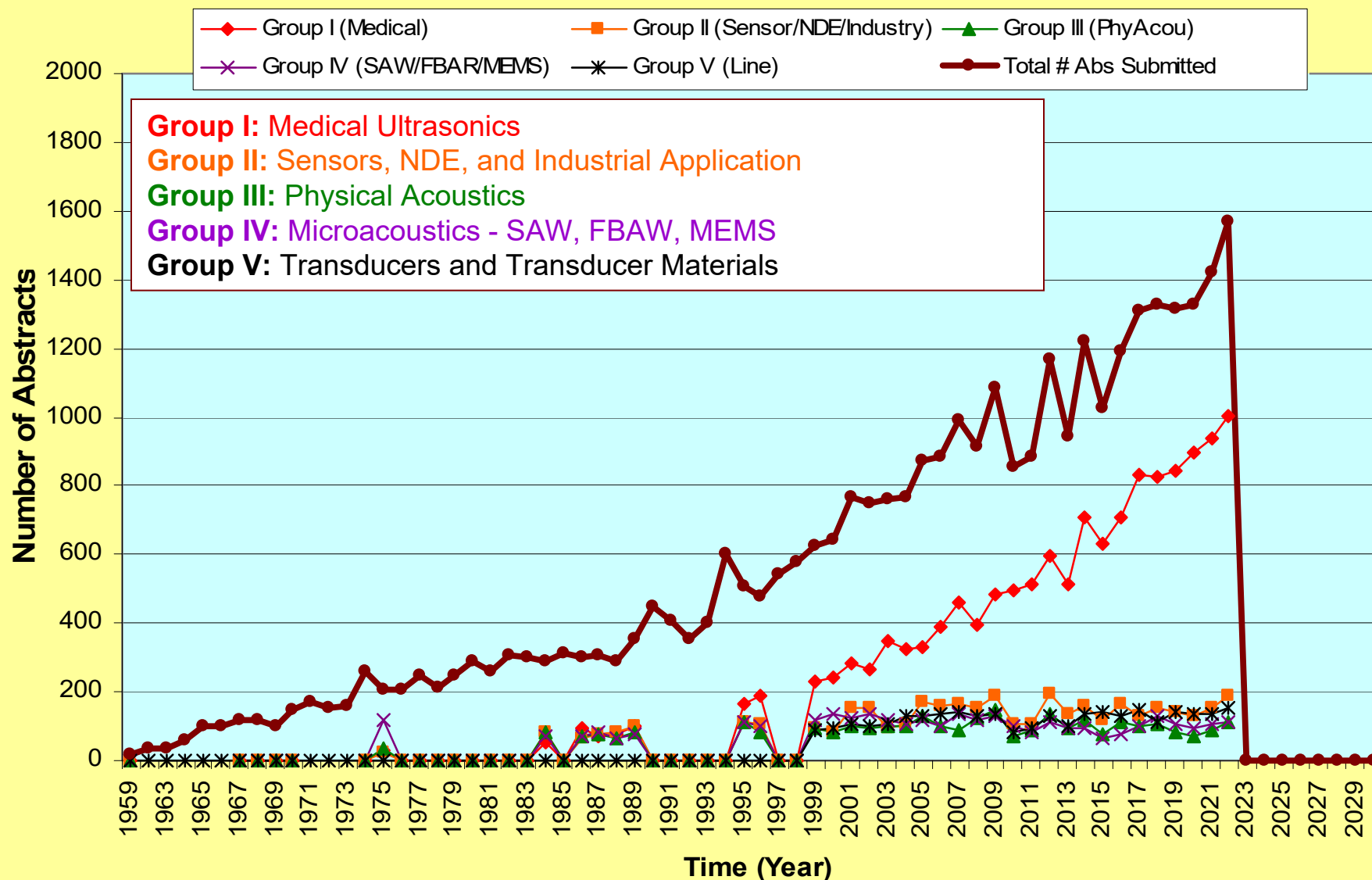
■ IEEE R1-7 (US/Canada)
 ■ IEEE R8 (Europe/MiddleEast/Africa)
 ■ IEEE R9 (LatinAmerica)
 ■ IEEE R10 (Asia/Pacific)
 ■ No Country



of Abstracts Submitted to the IEEE International Ultrasonics Symposia (IUS)
by Each Group (Since 1959) - "0" values mean that data are not available for those years;
 "Solid Bar" means no Group data

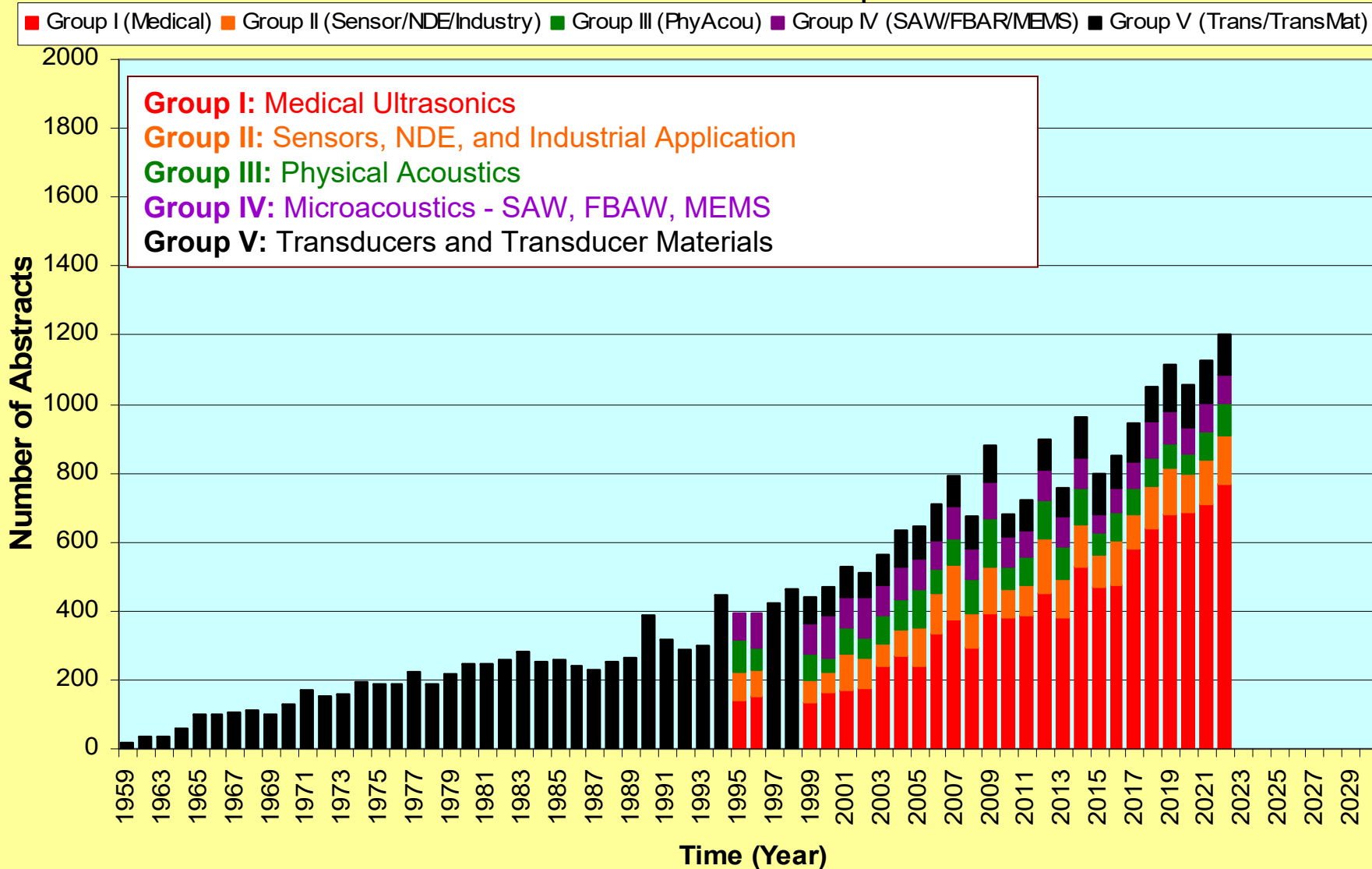


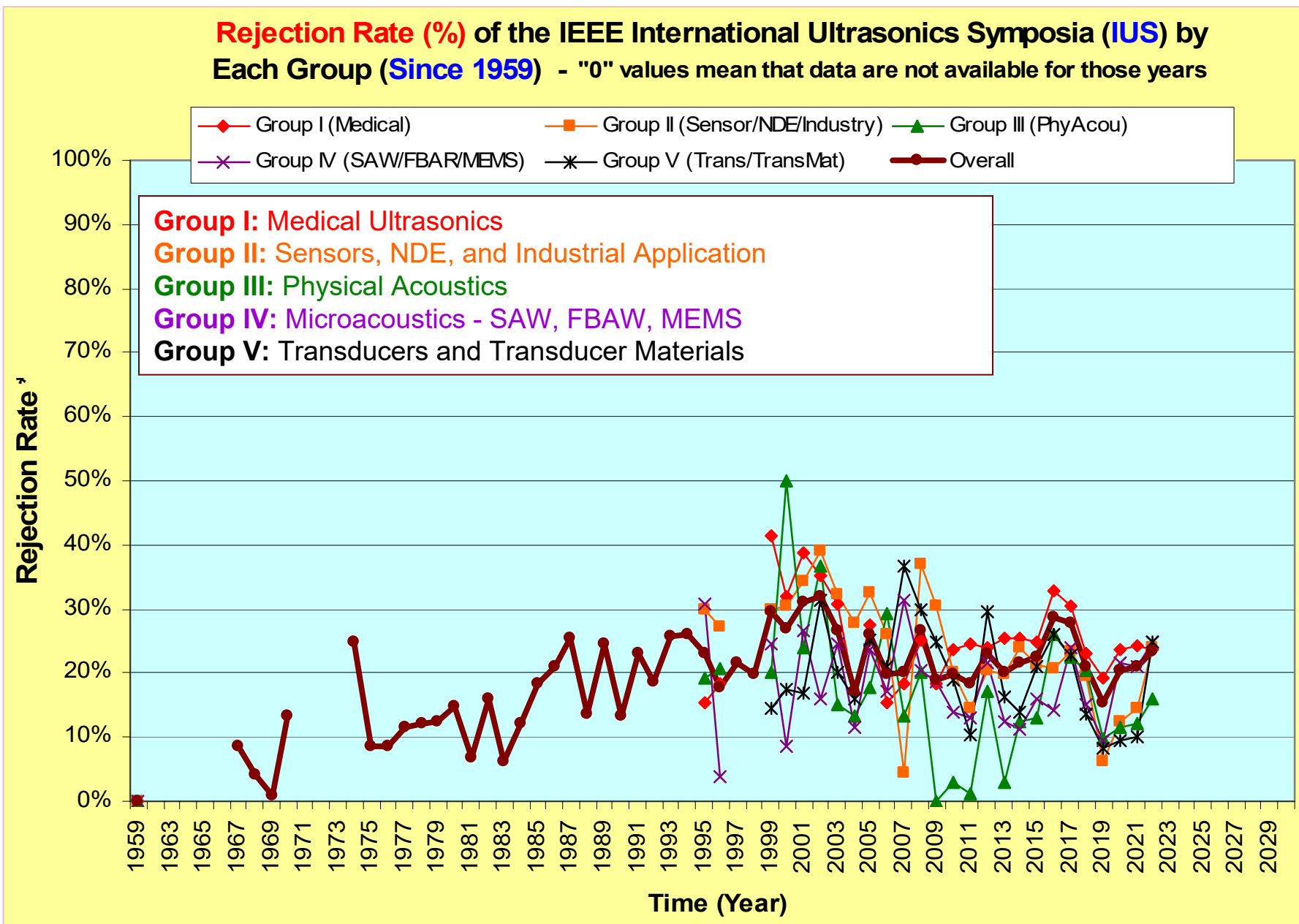
of Abstracts Submitted to the IEEE International Ultrasonics Symposia (IUS) by Each Group (Since 1959) - "0" values mean that data are not available for those years



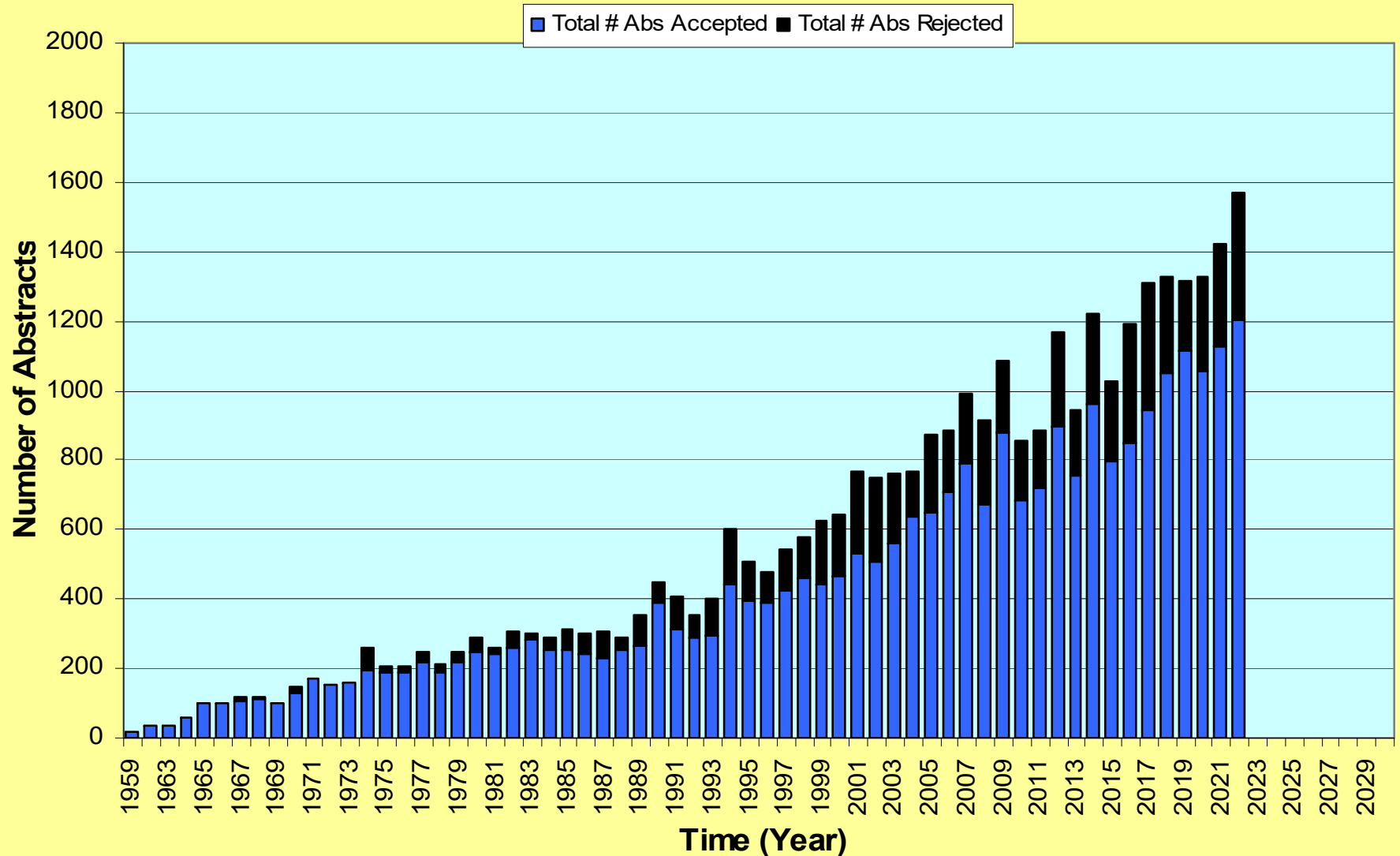
of Abstracts Accepted for the IEEE International Ultrasonics Symposia (IUS) by Each Group (Since 1959) - "0" values mean that data are not available for those years;

"Solid Bar" means no Group data

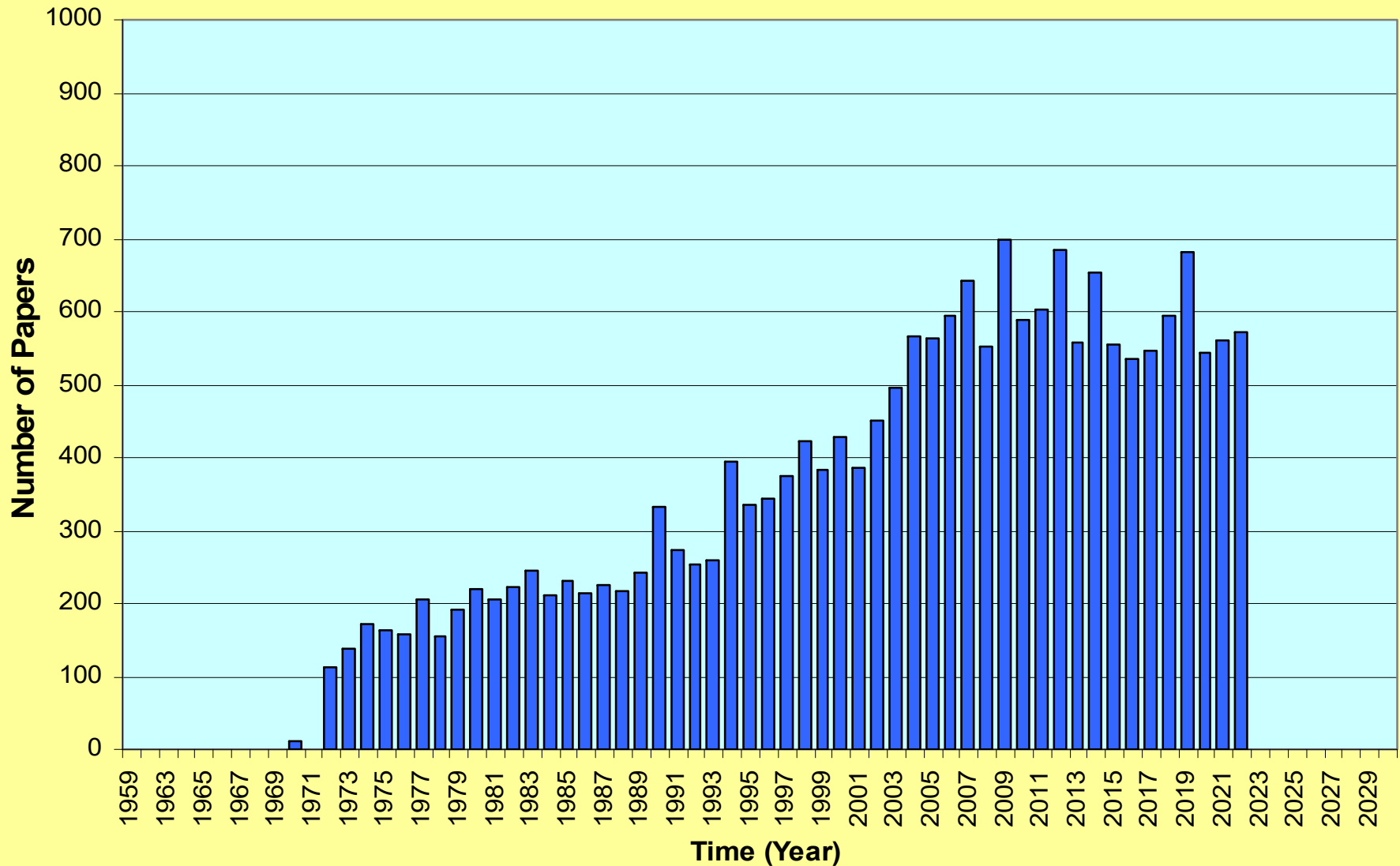


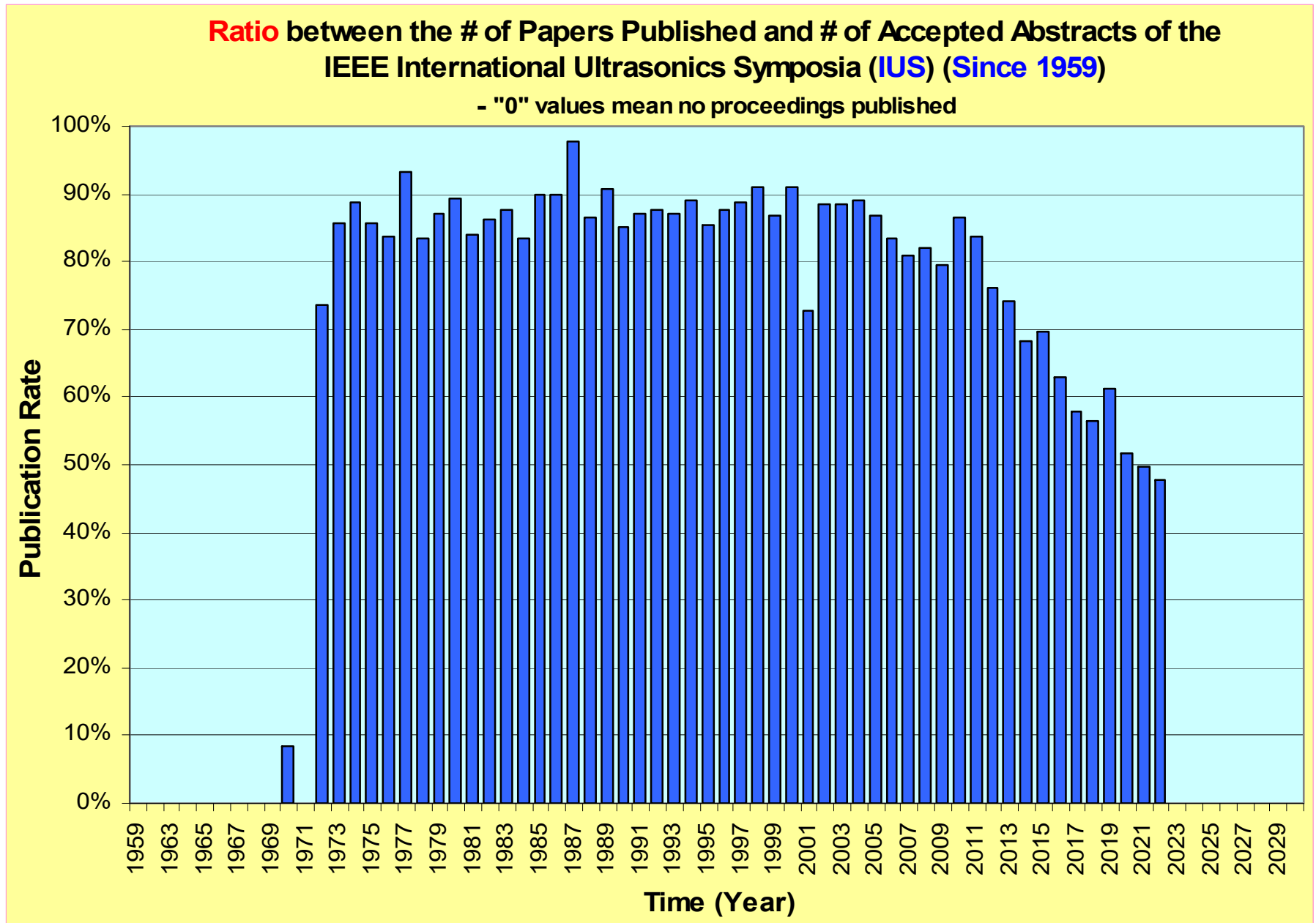


of Abstracts Accepted vs Rejected by the IEEE International Ultrasonics Symposia (IUS) (Since 1959) - "0" means that the rejection data are not available for those years

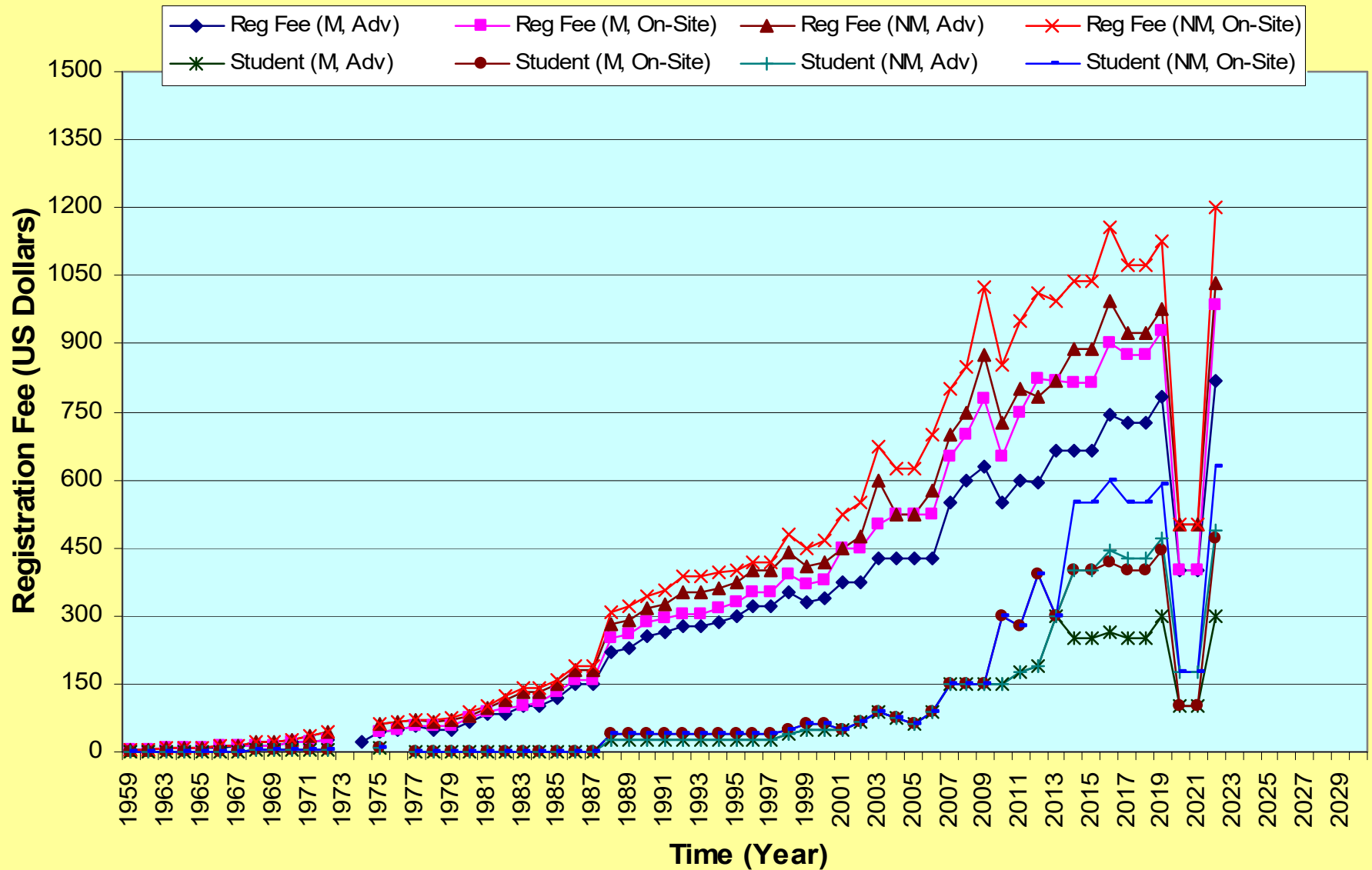


of Papers Published in the Proceedings of the IEEE International Ultrasonics Symposia (IUS) (Since 1959) - "0" values mean no proceedings published





Registration Fees of the IEEE International Ultrasonics Symposia (IUS) (Since 1959) - "0" values mean that data are not available for those years



Estimated **maximum** numbers of people attending **oral** sessions in each of the 5 technical groups of the **2008 IEEE IUS** from the data available (please notice that even within each Group, the maximum number of people attending each session is different, and also, the estimation for Group I may be lower than the real number. – These data have not been collected for other years since it is difficult to get such data and there are many variables for the accuracy of such data):

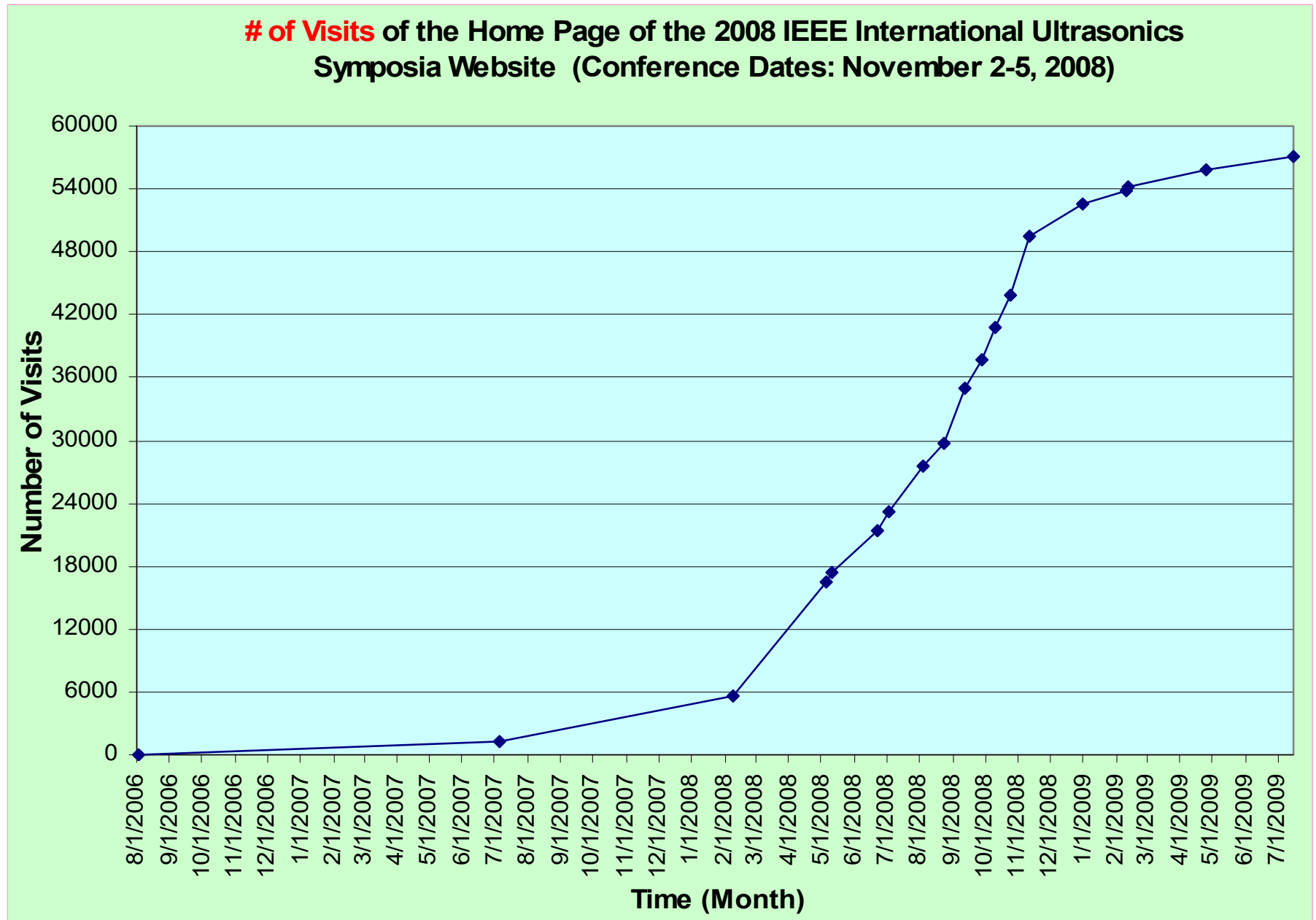
Group I: Medical Ultrasonics – 200

Group II: Sensors, NDE, and Industrial Application – 245

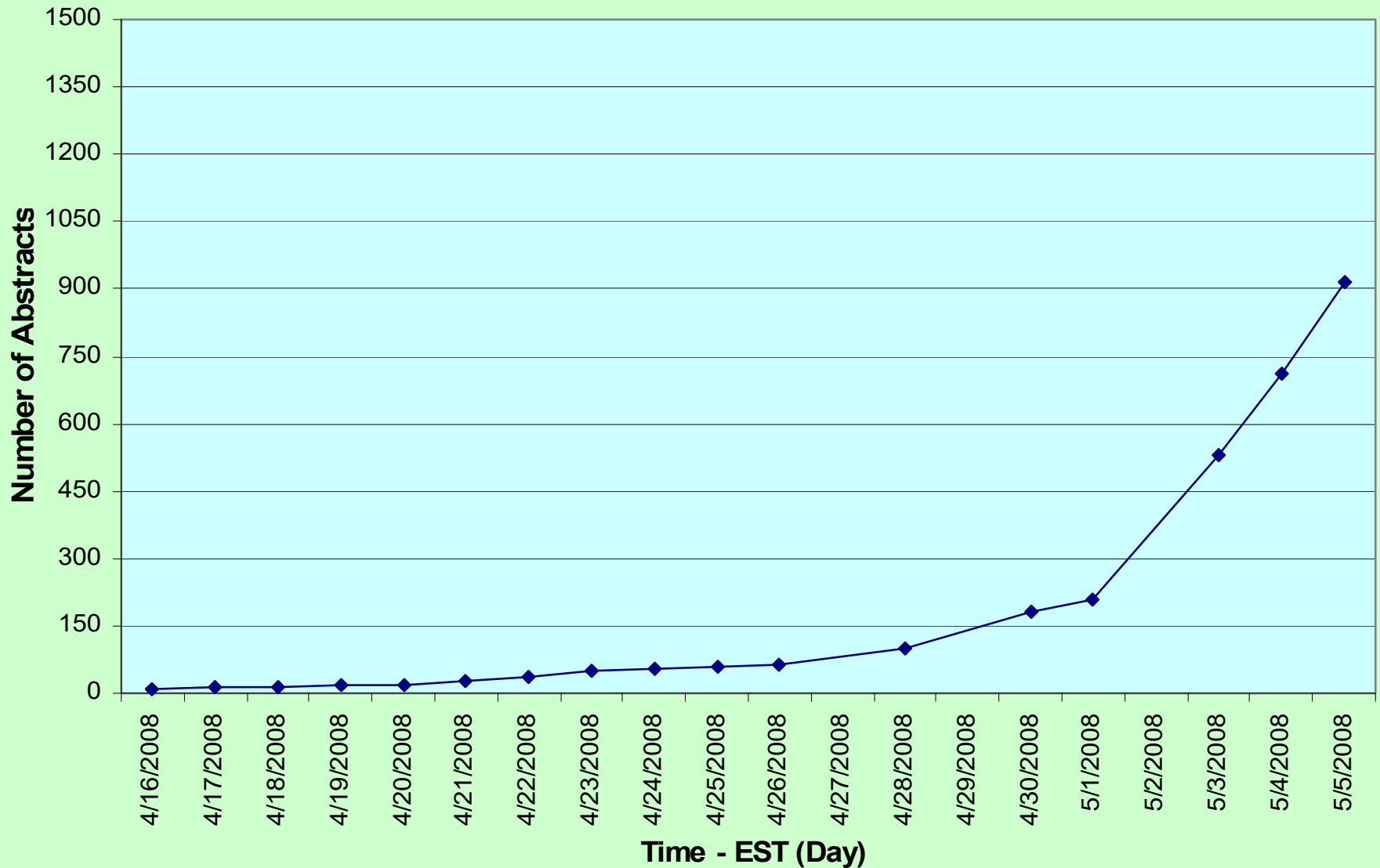
Group III: Physical Acoustics – 95

Group IV: Microacoustics - SAW, FBAW, MEMS – 150

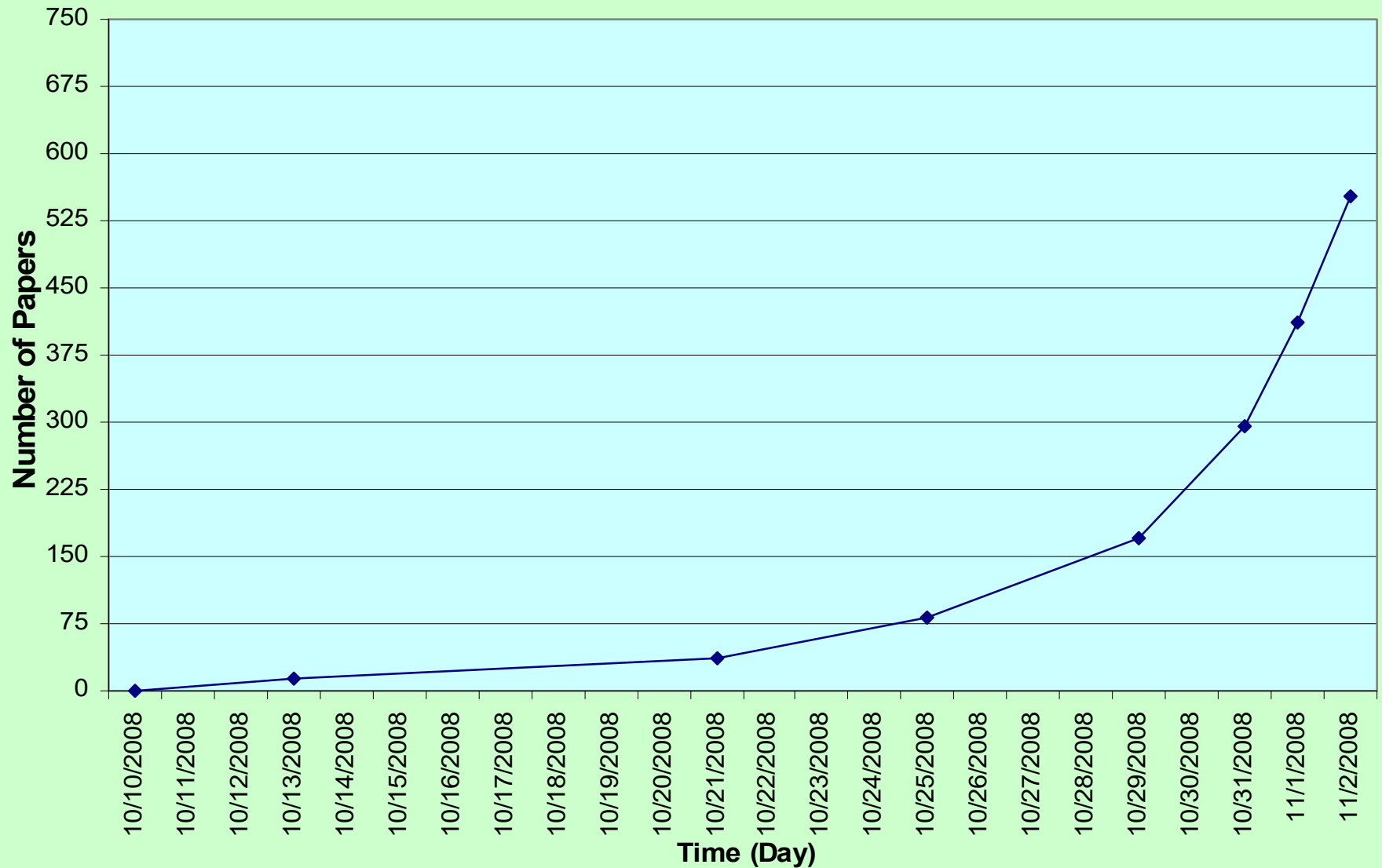
Group V: Transducers and Transducer Materials – 100

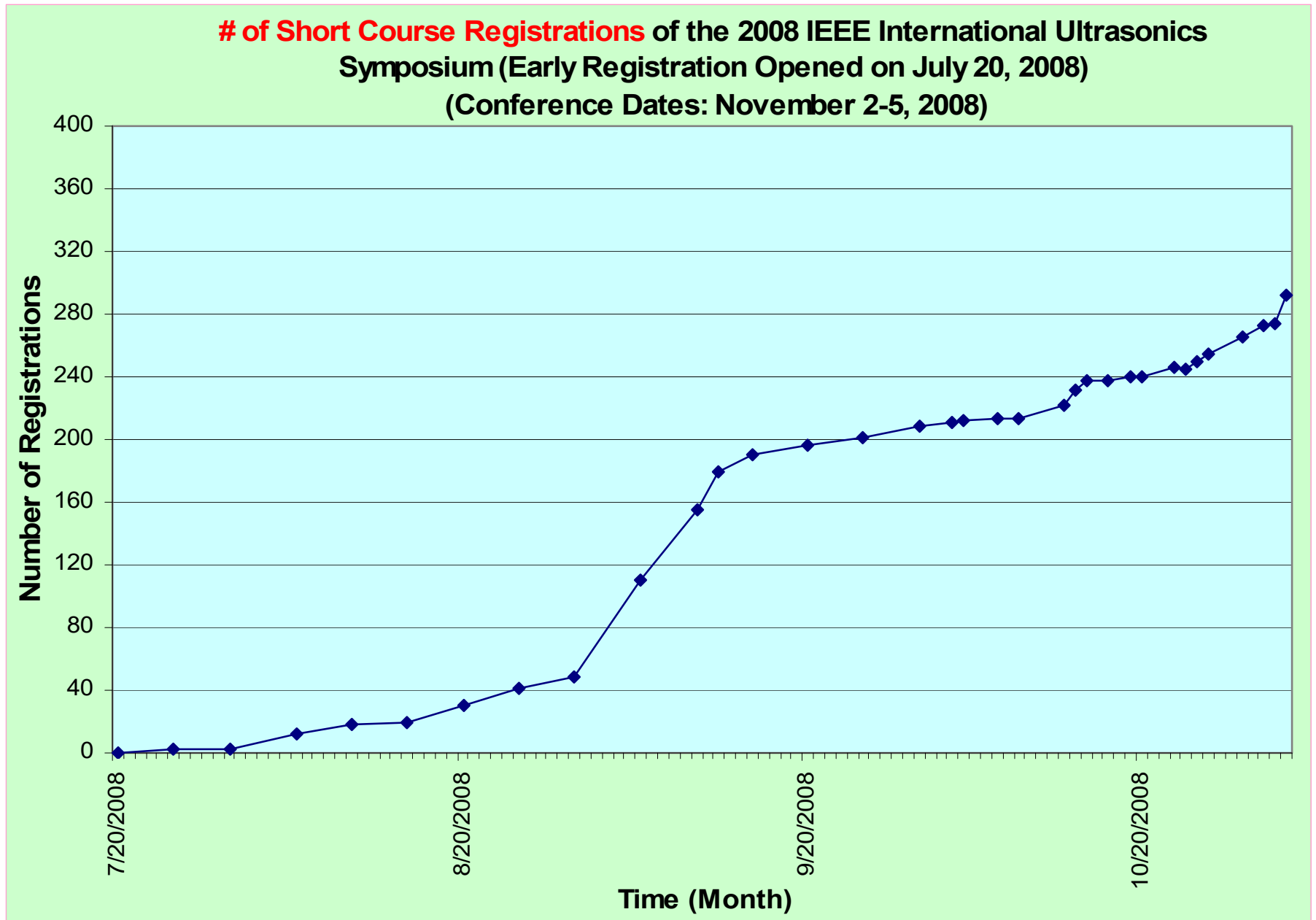


of Abstracts Successfully Submitted to the 2008 IEEE International Ultrasonics Symposium (Submission Deadline: May 4, 2008, PST / May 5, EST)



of Papers Submitted Successfully to the 2008 IEEE International Ultrasonics Symposium (Submission Deadline: Nov. 2, 2008, Beijing Time)





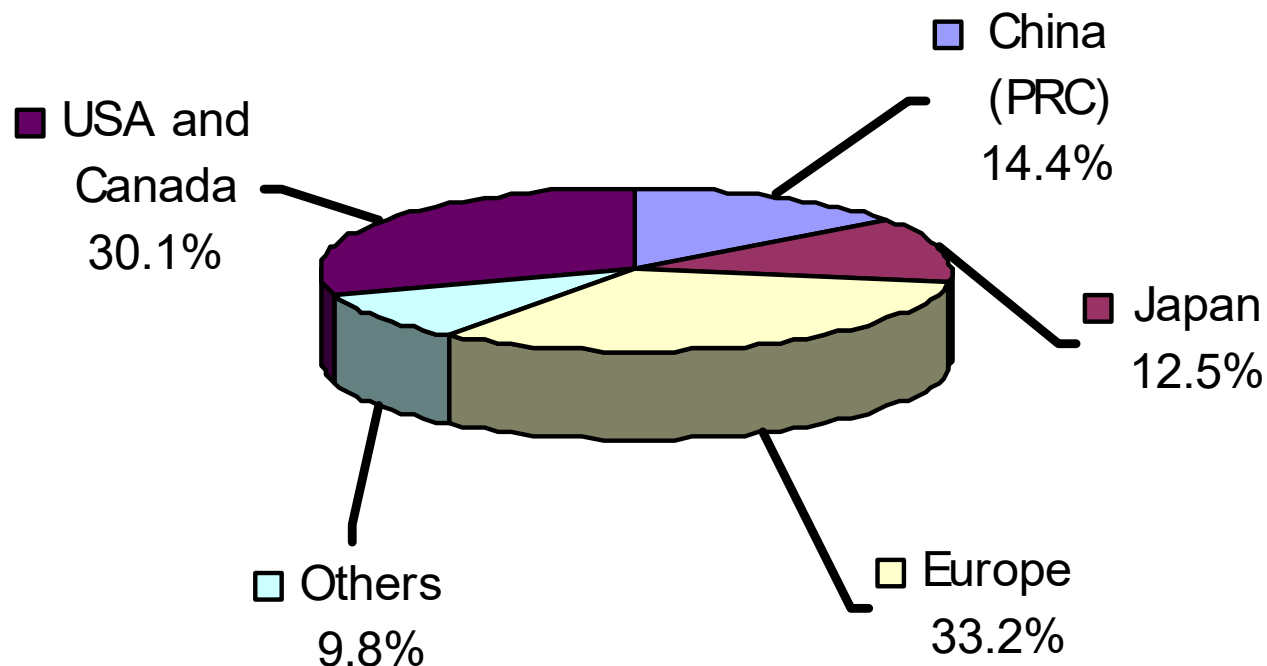
of Conference Registrations of the 2008 IEEE International Ultrasonics Symposium (Conference Dates: November 2-5, 2008)



1. Abstracts (674) accepted from 37 countries

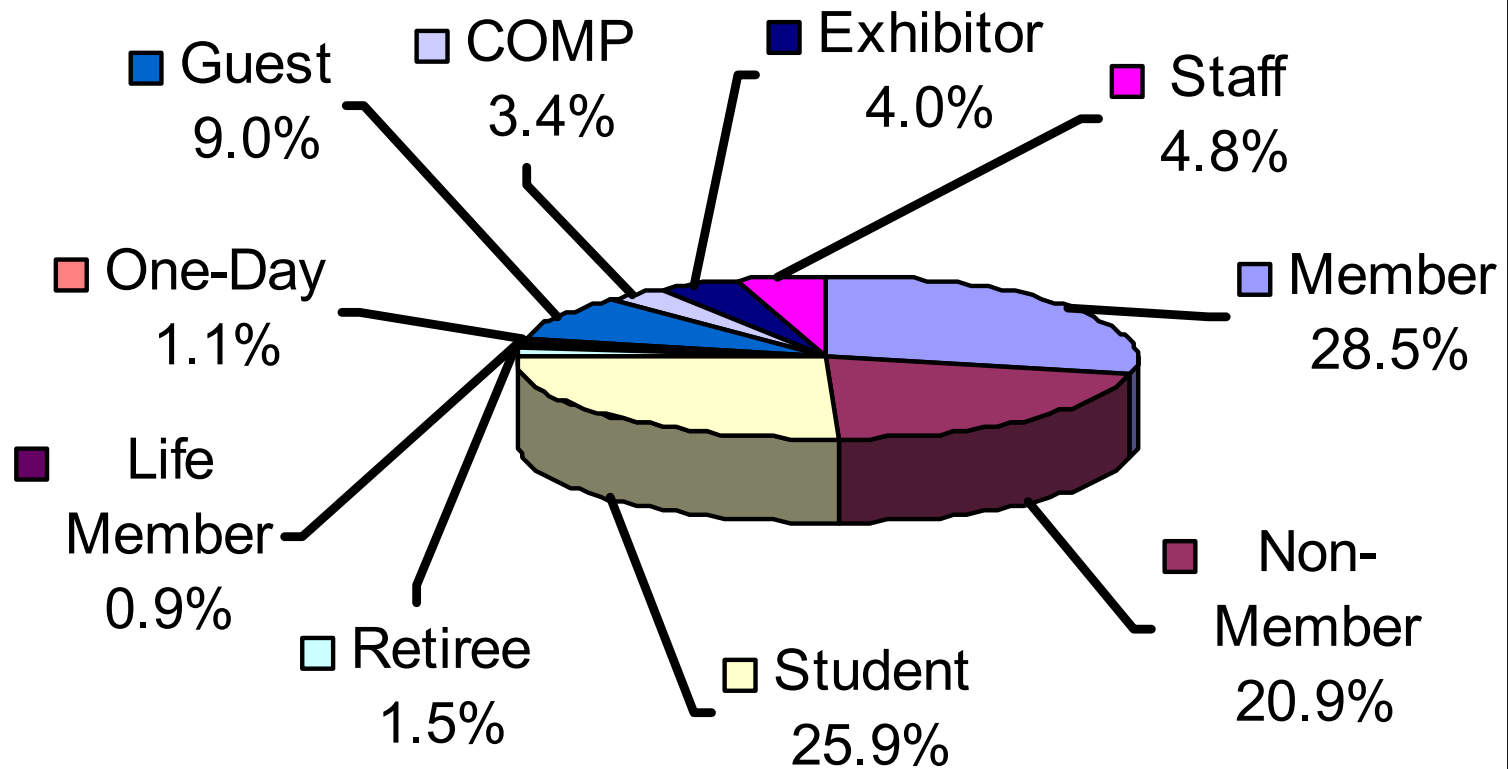
Accepted Abstract by Country in the Technical Program (Total 674)

(2008 IEEE IUS, Beijing, China, November 2-5, 2008)



2. Attendees (1023) in 10 categories

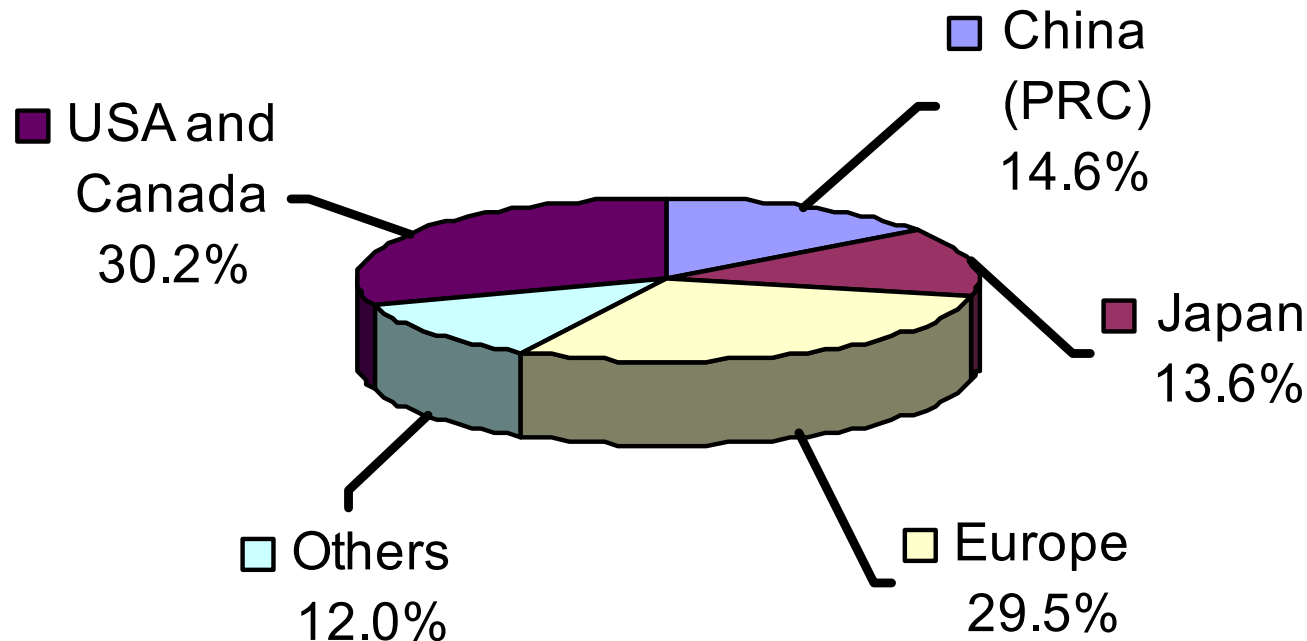
Registration Types (Total 1023 Attendees)
(2008 IEEE IUS, Beijing, China, November 2-5, 2008)



Note: Most “COMP” registrants are invited speakers

3. Conference Registration from 32 countries

Registration Distribution by Country (Excluding Staff and Exhibitors)
(2008 IEEE IUS, Beijing, China, November 2-5, 2008)

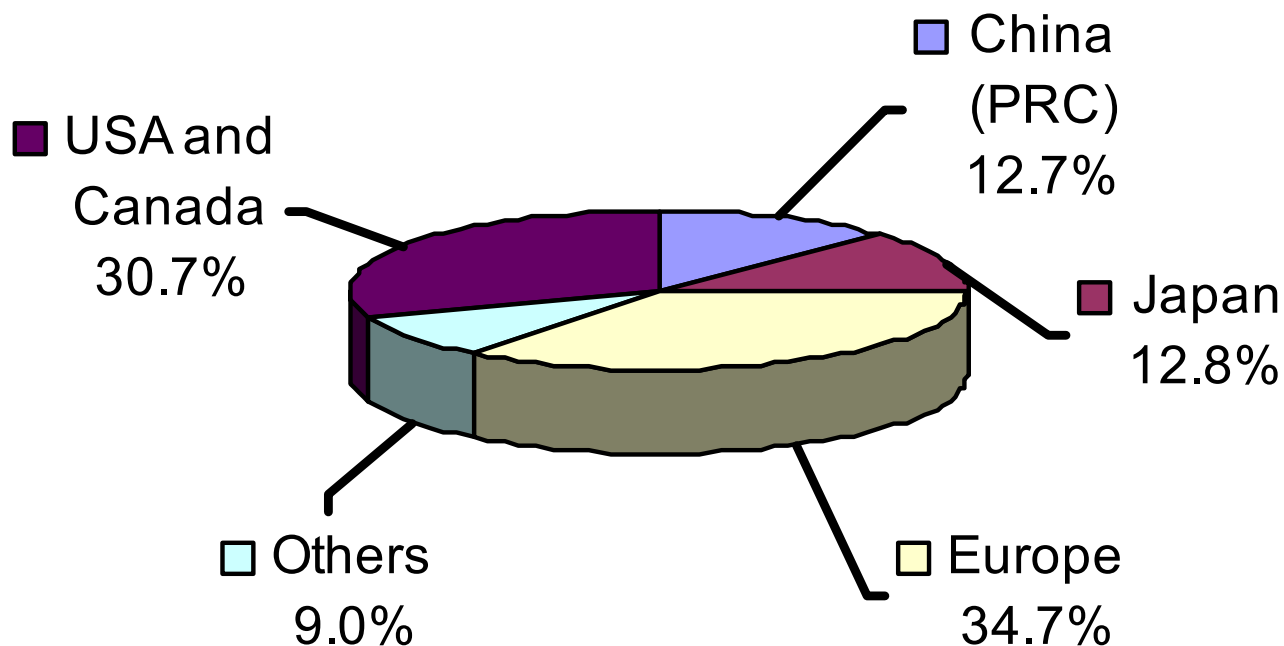


Note: The country counts of all charts do not include those of coauthors

4. Papers (553) published from 32 countries

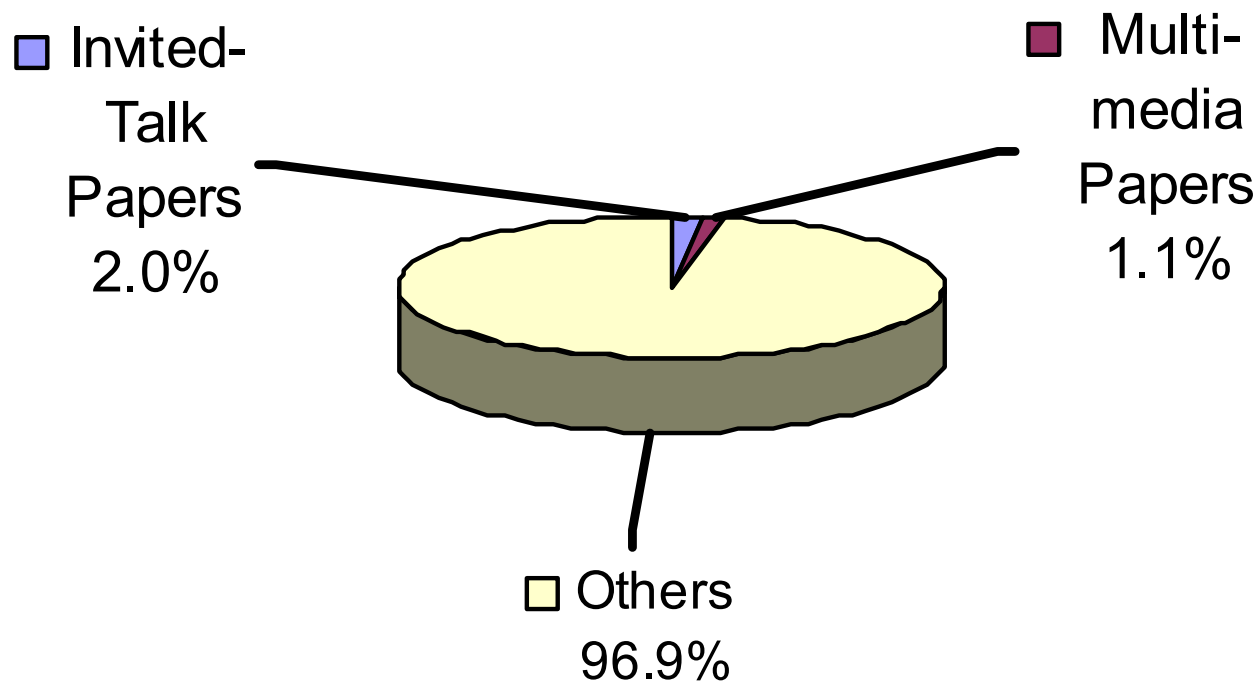
Number of Papers in Proceedings by Country (Total 553 Papers)

(2008 IEEE IUS, Beijing, China, November 2-5, 2008)



5. Papers (553) published in 3 categories

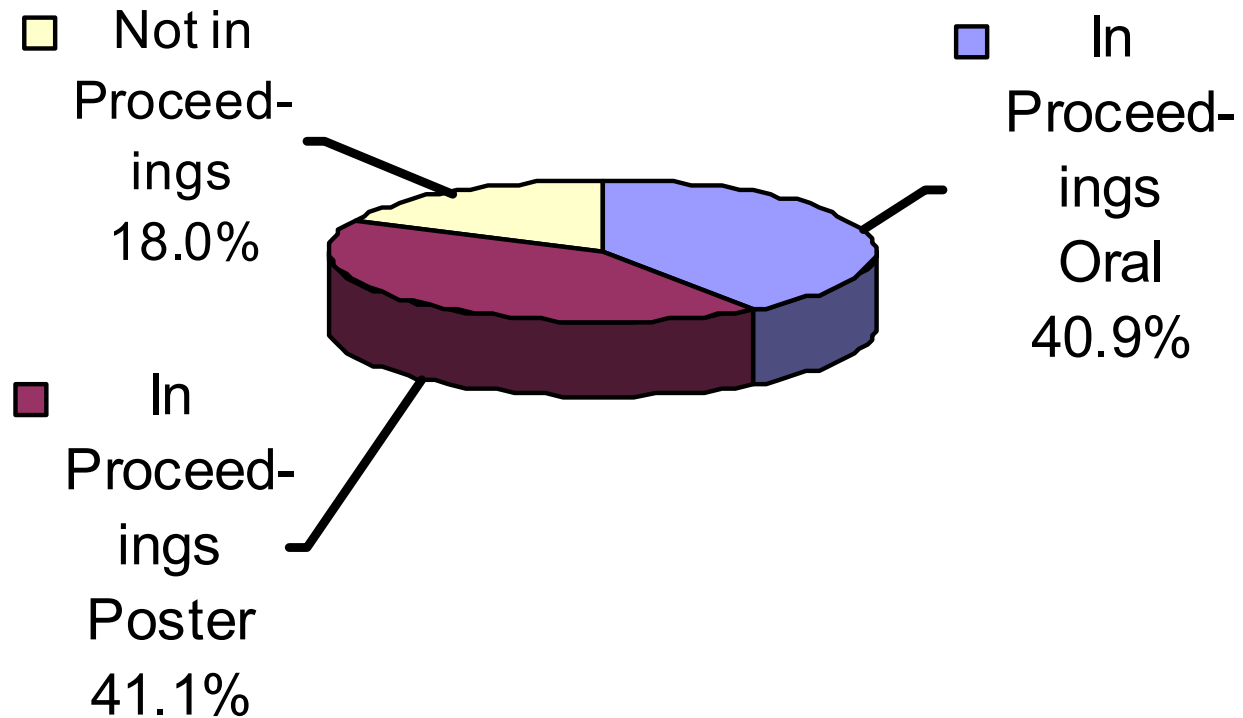
Paper Types in Proceedings (Total 553 Papers)
(2008 IEEE IUS, Beijing, China, November 2-5, 2008)



6. Papers (553) published from accepted abstracts (674)

Abstracts Statistics for Proceedings (Total 674 Abstracts)

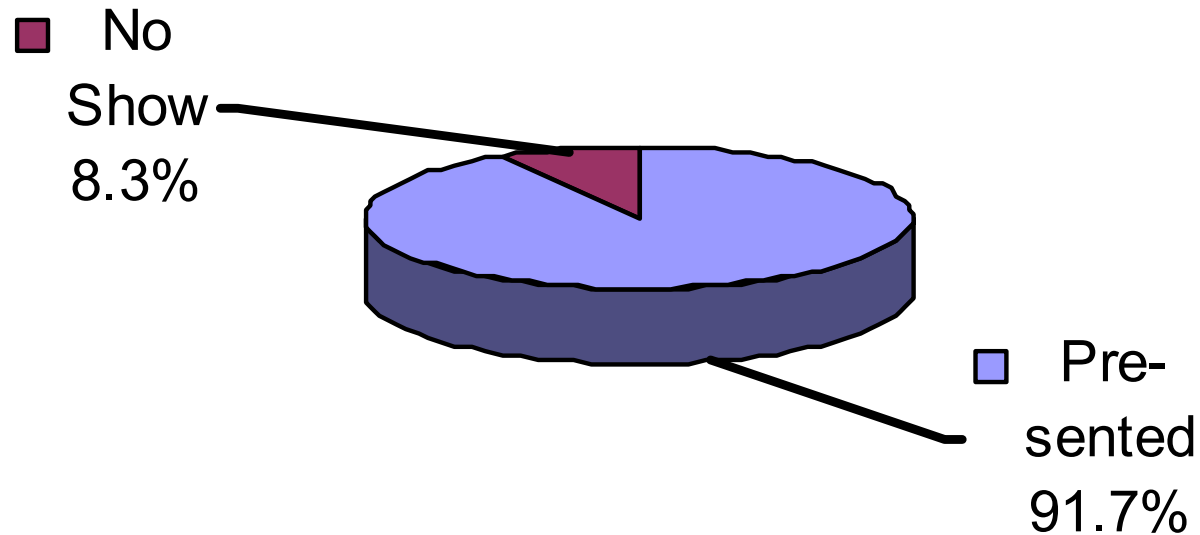
(2008 IEEE IUS, Beijing, China, November 2-5, 2008)



7. Presentations of accepted abstracts (674) in the conference

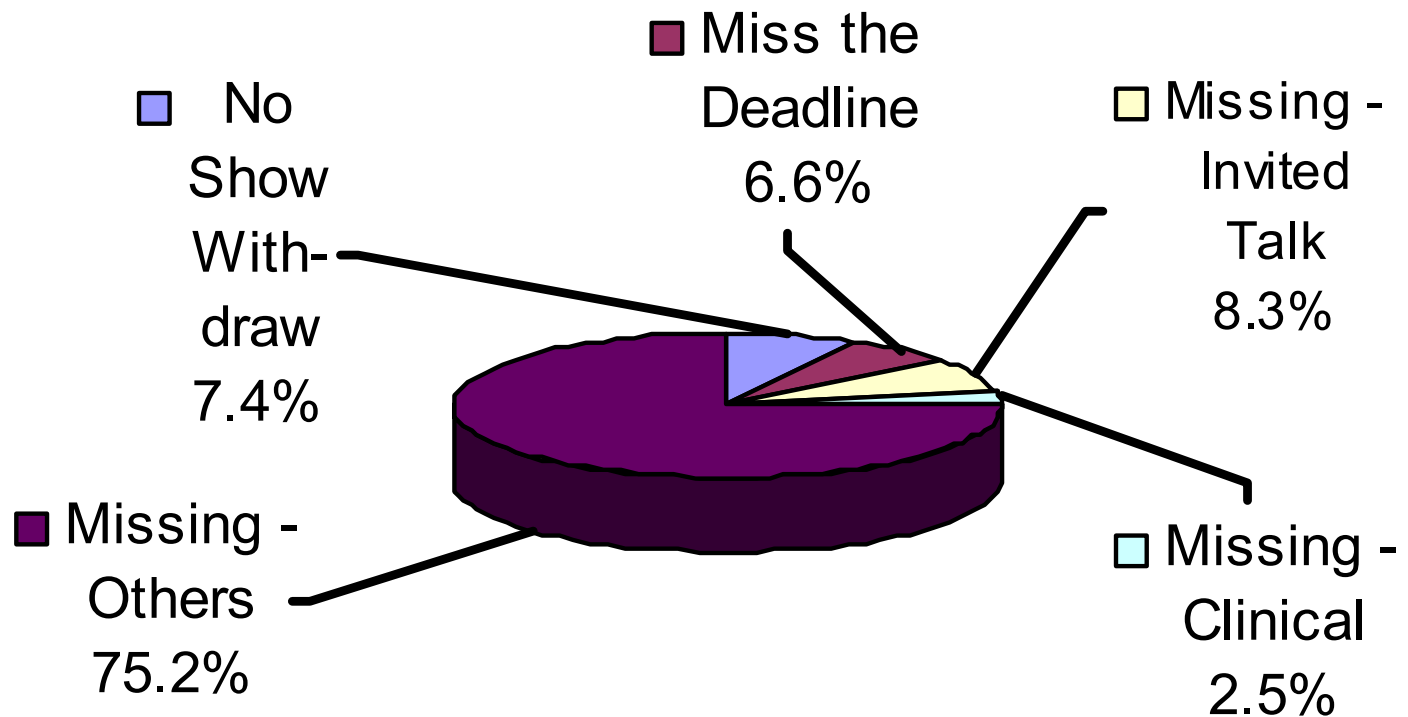
Abstract Presentation Statistics (Total 674 Abstracts)

(2008 IEEE IUS, Beijing, China, November 2-5, 2008)



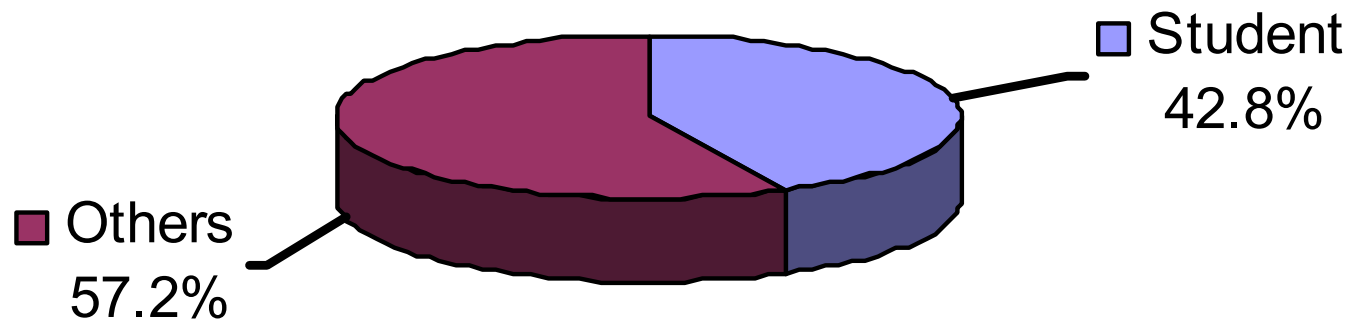
8. Categories of papers that are not published (121)

Papers Not in Proceedings (Total 121 Papers)
(2008 IEEE IUS, Beijing, China, November 2-5, 2008)

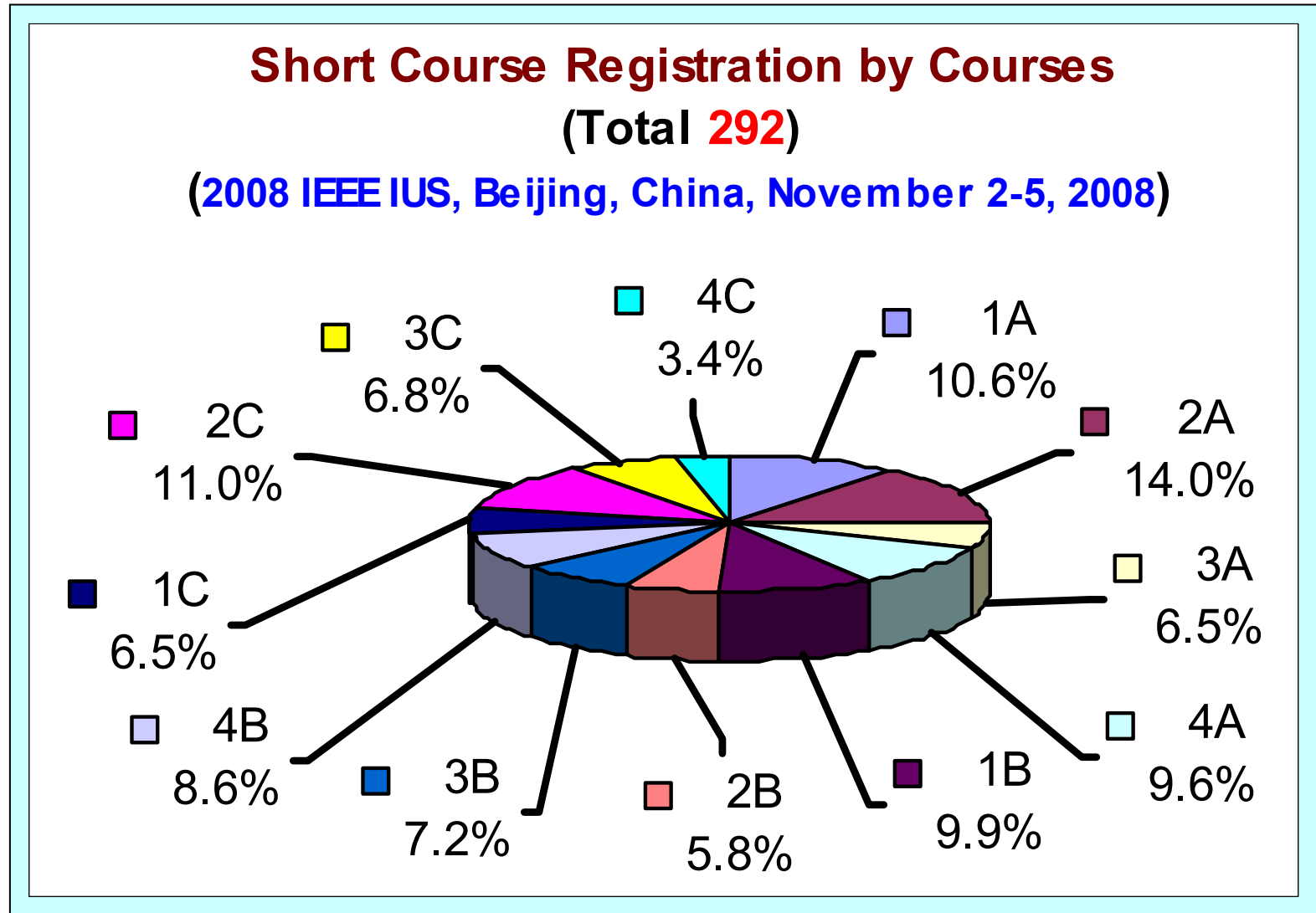


9. Short course registration (292) types

Short Course Registration Types (Total 292)
(2008 IEEE IUS, Beijing, China, November 2-5, 2008)



10. Attendances (total 292) of each of the 12 short courses



A list of the 12 short courses

- 8:00 A.M. - 12:00 Noon, Sunday, November 2, 2008:

Short Course 1A (Conference Room 311A/B): Medical Ultrasound Transducers, *Douglas G. Wildes* and *L. Scott Smith*, GE Global Research Center, Niskayuna, NY, USA.

Short Course 2A (Conference Room 307): Ultrasound Imaging Systems: from Principles to Implementation, *Kai E. Thomenius*, GE Global Research Center, Niskayuna, NY, USA.

Short Course 3A (Conference Room 308): Photoacoustic Imaging and Sensing, *Stanislav Emelianov*, Biomedical Engineering Department, University of Texas at Austin, USA.

Short Course 4A (Conference Room 311C): Estimation and Imaging of Tissue Motion and Blood Velocity, *Hans Torp* and *Lasse Lovstakken*, Department of circulation and medical imaging, Norwegian University of Science and Technology, Trondheim, Norway.

- 1:00 P.M. - 5:00 P.M, Sunday, November 2, 2008:

Short Course 1B (Conference Room 311A/B): Ultrasound Elastography: Quantitative Approaches, **Jeffrey Bamber* and ***Paul Barbone*, **Institute of Cancer Research and Royal Marsden Hospital, UK. **Boston University, USA.*

Short Course 2B (Conference Room 307): Acoustic Microscopy - Fundamentals and Applications, **Roman Gr. Maev*, ***Naohiro Hozumi*, ****Kazuto Kobayashi*, and *****Yoshifumi Saijo*, **Centre for Imaging Research and Advanced Materials Characterization, University of Windsor, Ontario, Canada. **Department of Electrical & Electronic Engineering, Aichi Institute of Technology, Toyota, Japan. ***Honda Electronics Co. Ltd., Aichi, Japan. ****Tohoku University, Sendai, Japan.*

Short Course 3B (Conference Room 308): Therapeutic Ultrasound, *Lawrence A. Crum*, Applied Physics Laboratory, University of Washington, Seattle, WA, USA.

Short Course 4B (Conference Room 311C): SAW Modeling Techniques, *Victor P. Plessky*, GVR Trade SA, Bevaix, Switzerland.

- 6:00 P.M. - 10:00 P.M, Sunday, November 2, 2008:

Short Course 1C (Conference Room 311A/B): Ultrasound Contrast Agents: Theory and Experiment, **Nico de Jong* and ***Michel Versluis*, **Erasmus MC, The Netherlands. **University of Twente, The Netherlands.*

Short Course 2C (Conference Room 307): CMUTs: Theory, Technology, and Applications, *B.T. Khuri-Yakub*, *Ömer Oralkan*, and *Mario Kupnik*, E.L. Ginzton Laboratory, Stanford University, USA.

Short Course 3C (Conference Room 308): Time Reversal Acoustics, *Mathias Fink*, École Supérieure de Physique et de Chimie de la Ville de Paris, France.

Short Course 4C (Conference Room 311C): Acoustical Near-Field Imaging, *Walter Arnold*, Fraunhofer Institute for Non-Destructive Testing, Saarbrücken, Germany.